

**MATERIALS CHARACTERIZATION TECHNIQUES FOR XRD AND XRF**  
**May 19th 2014**

**09:00 REGISTRATION**

**09:30 PRESENTATION OF THE SEMINAR**

Prof. Xavier Obradors (Director of ICMA B)  
Dr. Albert Llorente (PARALAB and RIGAKU)

**9:45 Prof. Jordi Rius (ICMA B-CSIC)**

*"Brief introduction to lab XRD and description of the new software for structure solution and refinement of polycrystalline materials downloadable from ICMA B webpage"*

**10:10 Dr. Carlos Frontera (ICMA B-CSIC)**

*"Structure refinement of thin films using lab equipment"*

**10:30 Dr. Oleksandr Slipeniuk (RIGAKU EUROPE)**

*"New Diffraction Equipment and last generation of detectors"*

**11:15 COFFEE BREAK**

**11:30 Dr. Ignasi Queralt (Laboratory of X-ray Analytical Applications, ICTJA-CSIC)**

*"Introduction to X-ray fluorescence spectrometry: Application to materials characterization"*

**12:15 Dr. Oleksandr Slipeniuk (RIGAKU EUROPE)**

*"Various types of XRF spectrometers"*

**13:00 SHORT COMMUNICATIONS**

**Prof. Elies Molins** (Director of Crystallography Dpt., ICMA B-CSIC)

*"Single crystal diffraction and electron density studies"*

**Dr. Oriol Vallcorba (ALBA)**

*"New structure solution possibilities of organic compounds from laboratory powder diffraction data"*

**Lcda. Anna Crespi (ICMA B-CSIC)**

*"New XRD applications in transmission mode at ICMA B"*

**14:00 CLOSING SPEECH**